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|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/750,534 | | Applicant(s)/Patent Under Reexamination DAVISON ET AL. | |
| | Examiner Maria Veronica D. Ewald | | Art Unit 1722 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,454,970 | 09-2002 | Ohman et al. | 264/1.33 |
| * | B | US-6,030,556 | 02-2000 | DePuydt et al. | 264/1.37 |
| * | C | US-2004/0202865 | 10-2004 | Homola et al. | 428/421 |
| * | D | US-4,723,903 | 02-1988 | Okazaki et al. | 425/385 |
| * | E | US-6,869,557 | 03-2005 | Wago et al. | 264/293 |
| * | F | US-2006/0051453 | 03-2006 | Imatomi, Yoshiyuki | 425/589 |
| * | G | US-6,210,514 | 04-2001 | Cheung et al. | 156/241 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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